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LIST OF REFERENCES CITED BY APPLICANT (Use several sheets if necessary)	ATTY. DOCKET NO. Y0987-074	SERIAL NO. 06/053,307
	APPLICANT J. G. Bednorz et al	
	FILING DATE 5/22/87	GROUP

U.S. PATENT DOCUMENTS

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EXAMINER	John Bzyl	DATE CONSIDERED	7/17/90

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EXAMINER <i>Joe Bp</i>	DATE CONSIDERED <i>5/17/93</i>
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